

**Notice of References Cited**

Application/Control No.

10/664,106

Applicant(s)/Patent Under  
Reexamination  
CHANG ET AL.

Examiner

Julian Mercado

Art Unit

1745

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*	N	WO 97/08763	03-1997		Yamashita et al.	H01M 2/16
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**NON-PATENT DOCUMENTS**

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